Search Notes			

Application/Control No.	Applicant(s)/Patent under Reexamination	_
10/734,420	LEE ET AL.	
Examiner	Art Unit	
John P. Trimmings	2138	

SEAR	CHED	
Subclass	Date	Examiner
		
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INT	INTERFERENCE SEARCHED		
Class	Subclass	Date	Examiner
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SEARCH NO (INCLUDING SEARCH)
·	DATE	EXMR
NPL Search: BIST, JTAG, memory test, authors.	7/27/2006	JPT
Dble Patent Search: Negative.	7/27/2006	JPT
Class Search: 714/30,25,710,718, 719,723,733,734. Text strategy attached.	7/27/2006	JPT
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